

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Hideo ANDO, et al.

SERIAL NO: New DIV Application

GAU:

FILED: Herewith

EXAMINER:

FOR: INFORMATION STORAGE SYSTEM CAPABLE OF RECORDING AND PLAYING BACK A PLURALITY OF STILL PICTURES

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were provided in previous U.S. Application Nos. 09/348,267, filed July 7, 1999, 09/630,430, filed August 1, 2000, and 10/076,284, filed February 19, 2002.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

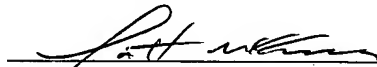
- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249700US2SDIV		SERIAL NO. New DIV Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,712,947	01/27/1998	<u>Oguro, et al.</u>			
	AB	6,385,389	05/07/02	<u>Maruyama, et al.</u>			
	AC	6,148,138	11/14/2000	Sawabe, et al.			
	AD	6,421,499	07/2002	Kim, et al.			
	AE	6,253,026	06/2001	Saeki, et al.			
	AF	6,389,222	05/2002	Ando, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AG	EP 1 065 665 A1	01/03/2001	European Patent Office (in English)			
	AH	JP 5-165935	07/02/1993	JAPAN	X		
	AI	JP 5-81787	04/02/1993	JAPAN	X		
	AJ	JP 7-143429	06/02/1995	JAPAN	X		
	AK	JP 8-106721	04/23/1996	JAPAN	X		
	AL	JP 9-259539	10/03/1997	JAPAN	X		
	AM	JP 11-215471	08/06/1999	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 <u>Maruyama, et al.</u>)			X
	AN	JP 11-238362	08/31/1999	JAPAN (corresponding European Patent No. EP 1 065 665, ANDO, et al.)			X
	AO	JP 5-158778	06/25/1993	JAPAN	X		
	AP	JP 5-165935	07/02/1993	JAPAN			X
	AQ	JP 8-205014	08/09/1996	JAPAN	X		
	AR	JP 9-182013	07/11/1997	JAPAN	X		
		JP 11-136613	05/21/1999	JAPAN	X		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AS	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English translation)					
	AT	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English translation)					
	AU	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English translation)					
	AV	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English translation)					
	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English translation)					
	AX						<input type="checkbox"/> Additional References sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,353,702	03/2002	Ando, et al.			
	AB	5,687,160	11/1997	Aotake, et al.			
	AC	5,731,852	03/1998	Lee			
	AD	6,185,365	02/2001	Murase, et al.			
	AE	6,067,400	05/2000	Saeki, et al.			
	AF	6,526,226	02/2003	Kashiwagi, et al.			
	AG						
	AH						
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	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2002-87033 (w/English translation)					
	AX	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-192063 (w/English translation)					
	AY	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-256210 (w/English translation)					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
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